# Double Probing Frequency Non-linear junction detector LORNET-0836



The non-linear junction detector LORNET-0836 is the indispensable tool for quick and reliable detection of devices containing semiconductor components. It can be used for counter-surveilance search works in premises (covert transmitters identification), as well as for location of explosive devices outdoors.

The DPF (**double probing frequency)** technology with a patent pending antenna system places it truly apart from the competition.

## Competitive advantages

- Duoble probing frequency operation mode gives Lornet-0836 significant advantages over single frequency NLJD since it is much better to detect small-sized and high-frequency semiconductor objects at high frequencies whereas the use of low frequencies benefits from improved detection in the wet ground and concrete walls;
- It is possible to operate in one of the frequency ranges and in both of them simultaneously;
- An embedded parabolic antenna with high gain (20 dB at 3600 MHz) enables highly precise detection of semiconductor components from a long distance (up to 10 m);
- Laser pinpointing for a space selective object localization;
- Wide power control range, automatic and manual modes of probing signal level adjustment;
- Possibility to listen to the envelope detector output as well as to the received signal level via a built-in loudspeaker and wireless headphones to evaluate parametric impacts (e.g. knocking) on the suspicious object.

## Specifications

| | |
|---|---|
| Type of probing signal | pulse |
| First probing signal frequency | 789,5 ... 791,5 MHz |
| Second probing signal frequency | 3581,5 ... 3607,5 MHz |
| Duty cycle | 0,3 % and 5% |
| Transmitters peak power in each frequency range | 18 W / 6 W |
| Receivers sensitivity | <-110 dBm |
| Operation time with changeable battery | >3.0 / 1,5 h |
| Dimmensions | 305 mm x 305 mm x 280 mm |
| Weight | <1,6 kg |